


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521773	<b>Applicant(s)/Patent Under Reexamination</b>  KANEKO ET AL.
	<b>Examiner</b>  John E Chapman	<b>Art Unit</b>  2856

SEARCHED			
Class	Subclass	Date	Examiner
73	493, 503, 504.04, 510, 514.01	4/2/2008	/JC/
33	366.12, 336.13	4/2/2008	/JC/

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner